



MAR 13 2007

Sheet 1 of 1

<b>FORM PTO-1449</b> (REV. 6-89) <b>INFORMATION DISCLOSURE CITATION</b> (Use several sheets if necessary)	U.S. DEPARTMENT OF COMMERCE Patent and Trademark Office		Attorney's Docket No. <b>4616 US</b>	Serial No. <b>09/724,633</b>
	Applicant <b>Bakker, et al.</b>			
	Filing Date <b>November 28, 2000</b>		Group Art Unit <b>To Be Assigned</b>	

### U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
<i>Aux</i>	A	5 2 2 6 1 1 8	07/6/93	Baker et al.	395	161	01/29/91

### FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
<i>Aux</i>	B	WO99/59200	18/11/99	PCT	-	-		
<i>Aux</i>	C	WO99/67626	29/12/99	PCT	-	-		
<i>Aux</i>	D	WO00/03234	20/01/00	PCT	-	-		

### OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>Aux</i>	E	Extended Kohonen Maps web pages [online] [retrieved on 1999-10-28]. Retrieved from the Internet: <URL: <a href="http://www.grid.let.rug.nl/~kleiweg/kohonen">http://www.grid.let.rug.nl/~kleiweg/kohonen</a> > 6 Pages
<i>Aux</i>	F	Karnowski, Thomas P., Tobin, Kenneth W., Gleason, Shaun S., Fred Lakhani "The Application of Spatial Signature Analysis to Electrical Test Data Validation Study" Oak Ridge National Laboratory, Oak Ridge, TN 37831-6011, Sematech, Austin, TX 78741-6499, 12 Pages
<i>Aux</i>	G	Electroglas.com web pages, "Spatial Pattern Recognition" [online] [retrieved on 2000-11-28]. Retrieved from the Internet: <URL: <a href="http://www.electroglas.com/products/knights_datasheets/spar_ds.htm">http://www.electroglas.com/products/knights_datasheets/spar_ds.htm</a> > 4 Pages
<i>Aux</i>	H	Dym.com web pages, "Spatial Signature Analysis (SSA)" [online] [retrieved on 2000-11-28]. Retrieved from the Internet: <URL: <a href="http://www.dym.com/ssa.htm">http://www.dym.com/ssa.htm</a> > 2 Pages
<i>Aux</i>	I	Oak Ridge National Laboratory web pages, "ORNL-SEMATAch Computing Tools Helps U.S. Semiconductor Industry Identify Manufacturing Problems" [online] [retrieved on 2000-11-28]. Retrieved from the Internet: <URL: <a href="http://www.ornl.gov/Press_Releases/archive/mr19980804-00.html">http://www.ornl.gov/Press_Releases/archive/mr19980804-00.html</a> > 2 Pages
<i>Aux</i>	J	ISMV Semiconductor web pages, "Semiconductor Spatial Signature Analysis (SSA)", [online] [retrieved on 2000-11-28]. Retrieved from the Internet: <URL: <a href="http://www.ismv.ic.ornl.gov/projects/SSA.html">http://www.ismv.ic.ornl.gov/projects/SSA.html</a> > 6 Pages.

EXAMINER	DATE CONSIDERED <b>3/15/04</b>
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EXAMINER: Initial references considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered.  
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